

U-3900/3900H





Spectrophotometer Meeting a Wide Range of Analytical Needs from Liquid to Solid Sample Measurements

- Measurable over a broad absorbance range thanks to low stray light and low noise. (Model U-3900: -3.8 to 3.8 Abs, 0 to 300%T Model U-3900H: -5.5 to 5.5 Abs, 0 to 300%T)
- Stable monochromator in double beam optics (Baseline flatness Model U-3900 : within ±0.0003 Abs, Model U-3900H : within ±0.0004 Abs)
- Simple instrument control and diversified quantitative analysis supported by UV Solutions program for U-3900 (in connection with PC)
- A full range of accessories for covering both liquid and solid sample measurements

Single monochromator

Stray light : 0.015% or less Photometric range : -3.8 to 3.8 Abs

> Two types available for selection according to sample and application purpose. Usable over an extensive field including analyses of water quality, the environment, biotechnology, drug manufacture and materials.



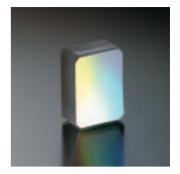
Stray light : 0.00025% or less Photometric range : -5.5 to 5.5 Abs

Adoption of Stigmatic Concave Diffraction Grating

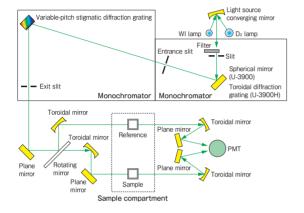
Hitachi Model U-3900/U-3900H spectrophotometer adopts a Seya-Namioka mount monochromator and a stigmatic concave diffraction grating.

Because a concave diffraction grating is usable for both converging and dispersing light, it allows composition of an optical system with a small number of mirrors.

In this design, loss of light and aberration are suppressed, so a bright optical system can be configured.



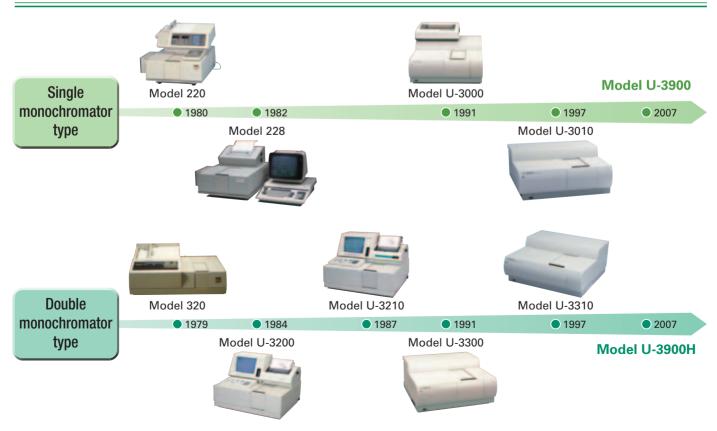
Stable Optics with Double Beam



As a light source, a WI lamp (visible region) and a D₂ lamp (ultraviolet region) are provided for selective use according to measuring wavelength range.

Double beam optics is adopted for ensuring stable measurements, in which the monochromatic beam selected with a monochromator is split into reference beam and sample beam with a rotating mirror (sector mirror) and the beams are directed into the sample compartment. In one model, the U-3900, a spherical mirror is used before the entrance slit. In the other model, the U-3900H, a grating is used before the entrance slit.

Since the Model 320 was launched in 1979, Hitachi medium-size spectrophotometers have been employed by customers in 25 countries.



Hardware

Hardware structure with priority given to ease of operation and data reliability.

Hardware structure attaching greater importance to ease of operation

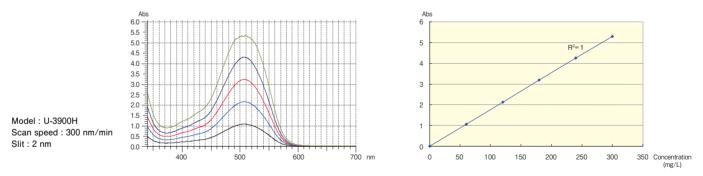
USB communication is adopted between the spectrophotometer and PC. And, because the top face of the spectrophotometer is flat, a notebook PC can be mounted on it. Therefore, the spectrophotometer and PC can be connected promptly.





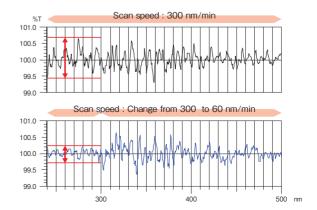
Incorporation of double monochromator

Due to mounting of a double monochromator which uses Hitachi's original stigmatic concave diffraction grating, an excellent linearity is ensured up to high concentrations. Hence, highly reliable quantitative analysis is possible.



Measurement with change in scan speed for ultraviolet region

Scan speed is changeable for the ultraviolet region. In this wavelength region, noise can be reduced by slowing down the scan speed. Owing to this feature, a noise-suppressed spectrum is obtainable over the entire range from visible to ultraviolet region by a single scan.

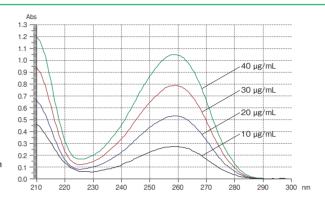


Effective in trace sample measurement

Satisfactory measurement is achievable even with 5, 25 and 50 µL micro-sample cells because the beam is finely converged in the sample compartment.

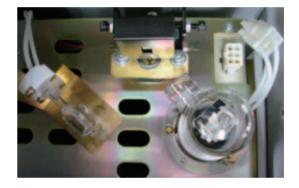
Shown here are spectra determined in the ultraviolet region by measuring nucleic-acid adenosine with a micro-sample cell (internal volume 25 µL). A high S/N ratio was obtained.

> Model : U-3900 Scan speed : 300 nm/min Slit: 2 nm



Ease of maintenance (in lamp replacement)

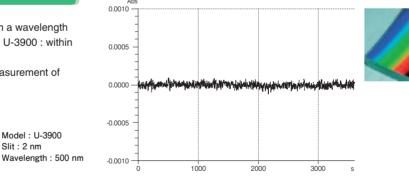
Lamp cable is connected by means of a socket, so each lamp can be removed or inserted without using a tool such as flat-head screwdriver.



Stable baseline

The Model U-3900 series assures a stable baseline in a wavelength range from 190 to 850 nm. (Baseline flatness Model U-3900 : within ±0.0003 Abs, Model U-3900H : ±0.0004 Abs)

Data can be measured stably even in a long-time measurement of enzyme activity, etc.

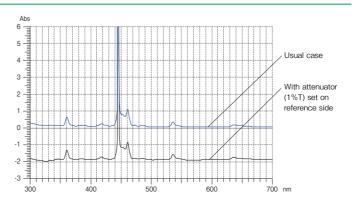


Original differential feedback system

Sample signal, reference signal and zero point rise are always monitored and photomultiplier voltage is changed so that the sample or reference signal, whichever larger, becomes constant, whereby minus absorbance can be measured. Also, measurement in a broad dynamic range is allowed, e.g., difference spectrum measurement with different samples set on reference and sample sides.

> Model : U-3900H Scan speed : 300 nm/min Slit · 2 nm

Model : U-3900 Slit: 2 nm



Software

"UV Solutions for U-3900" program has been prepared for efficient instrument control and various quantitations.

A series of operations from analysis method setup to data processing can be initiated by clicking each button.

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	Method
55 30 10	Measure



Analysis method setup window

Clicking this button enables the user to set analytical conditions such as measurement mode, measurement range and scan speed.

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Baseline measurement

Baseline measurement procedure can be started by clicking this button.

Upon measurement, data after baseline correction is obtainable.



Sample information setting

Clicking this button allows setting of detailed information about a sample to be measured, data saving location, etc.

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Measurement start

Measurement can be started by clicking this button.



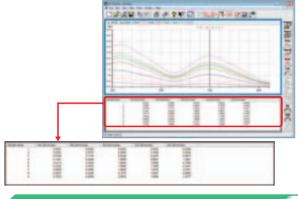
Reporting

Data file can be output in a report format by clicking this button.

Enriched functions such as data comparison and preview are supported by UV Solutions for U-3900.

Easy comparison of measured data

Measured data can be compared easily by overlaying spectra or in Abs value at the specified wavelength. (A maximum of 10 spectra can be compared at 12 specified wavelengths).

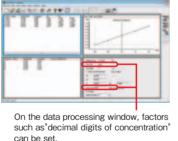


Factor of data processing (quantitation) changeable

"Correction factor," "decimal digits of concentration" and "concentration unit" are settable on the sample table window.

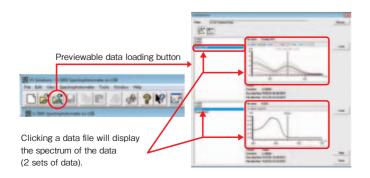
Setting can be determined in consideration of a sample to be measured, its concentration, etc.





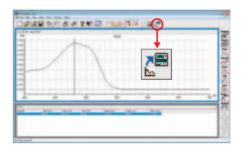
File loading function with preview

Using a tool button for file loading with preview, max. two sets of data can be previewed without opening data files.



Reuse of analysis method for measured data

When it is desired to carry out measurement by the same analysis method as used for the already measured data, the "Apply analysis method" button is usable. The analysis method can be loaded and applied to a new measurement by clicking this button.



Control of lamp ON time

Total operation (ON) time of the WI and D₂ lamps used in the U-3900 series can be checked on the software. This time counting is usable as a reference for judging the replacement time point for each lamp.

Lamp Usage		
D2 Lamp: 0	h	Reset D2 Lamp
WI Lamp: 0	h	Reset WI Lamp
	Close	

Measured data exportable to commercially available software

Data such as measured spectrum can be pasted to Microsoft[®] Word and Microsoft[®] Excel[®], and converted into an ASCII text file. Using such software, a report form can be edited.

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More Function with U-3900/3900H spectro-photometer

Enhanced large sample compartment Accessory

When installing this enhanced sample compartment and additional accessories in U-3900/U-3900H UV-VIS spectrophotometer, you can measure the reflection characteristic, polarization property caused by incidence angle and transmission of solid sample and optical component, like reflected plate. With using ϕ 60mm integrating sphere, diffusely emitted light from sample are detected in this instrument. With this enhanced sample compartment, it is possible to measure solid sample ϕ 120mm at maximum. In addition, when installing 5° /45° specular reflection accessory, specular reflection measurement can be realized.



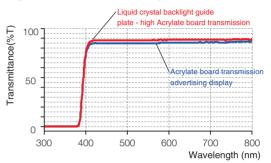
Realize 190 to 1100nm range wavelength measurement

When changing to near infrared corresponding detector in U-3900/U-3900H spectrophotometer, you can measure samples which has absorption wavelength between 190 to 1100nm. For example, you are able to evaluate transmission around 940nm which is used for received wavelength of remote control. And more, phosphoric acid measurement, which is difficult to measure with standard detector, become available.

%Т 100-90 80 70 60 940 nm 50 40 30 20 10 0 300 400 500 600 700 900 1.000 1.100 200 800 wavelength (nm)

Transmission spectrum of filter used for remote control

Acrylate board transmission spectrum

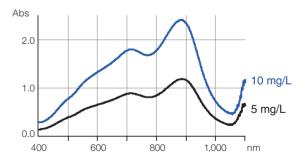


Accessory: Glass filter holder

2 types of acrylate board, advertising display and liquid crystal backlight light guide plate, transmission spectrum were measured. Both sample indicated flat transmission feature in VIS area, it shows liquid crystal backlight guide board has better transmission.Compare to common acrylate board, light guide plate is required for high transmission of visible light. Enhanced large sample compartment enables you to measure large sample's transmission.

P/N	Description	Voltage
2J2-0022	U-3900 with Enhanced large sample compartment	115 V
2J2-0023	U-3900 with Enhanced large sample compartment	220 to 240 V
2J2-0041	U-3900H with Enhanced large sample compartment	115 V
2J2-0042	U-3900H with Enhanced large sample compartment	220 to 240 V

Absorption spectrum of phosphoric acid standard solution



P/N	Description	Voltage
2J2-0122	U-3900 with 1,100 nm Version Modification Kit	115 V
2J2-0123	U-3900 with 1,100 nm Version Modification Kit	220 to 240 V
2J2-0131	U-3900H with 1,100 nm Version Modification Kit	115 V
2J2-0132	U-3900H with 1,100 nm Version Modification Kit	220 to 240 V

Accessories Expediting Application to Multi-Sample Measurement, Micro-volume Sample and Many Others

Micro cell holder

(P/N 122-0060)

Suitable for micro-sample measurement in medical and biochemical fields.

Specifications

Wavelength range	220 to 800 nm			
Repeatability in cell placement	Within ±0.3%T			
Baseline flatness	Within ±0.0025 Abs			
Dasenne nauless	(when using 50 µL micro-sample cell)			

Micro-sample cell

The following cells are usable for the micro-sample cell holder.(P/N 122-0060)

Part No.	Part name	Capacity	Optical path length
130-0622	50 µL cell	50 µL	10 mm
130-0623	25 µL cell	25 µL	5 mm
130-0621	5 µL cell	5 µL	0.5 mm

Auto sipper (P/N 2J1-0105)

This computer-controlled sample sipper is provided with a sample recovery function and other versatile functions. In combination with an autosampler, this unit makes it possible to carry out automated labor-saving analysis.

opecifications			
Minimum sample volume	0.6 mL		
Carryover	1% or less		
Cell capacity	Approx. 50 µL		
Sample beam side	Flow cell(Path leyth:10 mm)		
Reference beam side	10 mm rectangular cell mountable		

*:Exchangeable with 10mm retangular cell holder (standard equipment). Cell is not included.

Electronic thermostatted auto sipper (P/N 2J1-0106)

The flow cell section is maintained at a constant temperature level under accurate control.



Specifications	(reference	beam	side	not	temperature-controlled)

Minimum sample volume	0.6 mL
Carryover	1% or less
Cell capacity	Approx. 50 µL
Sample beam side	Flow cell (Path leyth:10 mm)
Setting temperature	20 to 40°C
Setting accuracy	Within ±0.5°C
Reference beam side	10 mm rectangular cell mountable

*:Exchangeable with 10mm retangular cell holder (standard equipment). Cell is not included.

AS-1010 autosampler (P/N 2J1-0121/0122)

This unit is used for multiple-sample measurement in combination with an auto sipper or in flow injection analysis. A suction needle can be moved in three directions X, Y and Z.



Specifications

Sample tube size Outside diameter 15 mm, height 105 mm (option required) Outside diameter 12 mm, height 105 mm

*:Sample tube not included

Water circulated cell holder (P/N 210-2111)

Water from a thermostatic oven is circulated through this cell holder to maintain a sample cell at a constant temperature.

(Temperature control : R and S)



Specifications

Operating temperature range	Room temperature to 40°C	
Temperature stability	Within ±0.3°C	
*Circulatory thermestatic even and cell not included		

Electronic thermostatted cell holder (P/N 131-0306/0307)

This cell holder comes standard with an incorporated magnet stirrer. The temperature of sample in a cell is maintained at a constant level, and a temperature value down to 0.1°C can be indicated. Since this unit is of electronic thermostatted type with forced air cooling, quick heating and cooling can be performed without a water circulating thermostatic oven. (Temperature control : S only)



Specifications

Temperature range	10°C to 60°C (settable in increments of 0.1°C, under condition of 25°C room temperature)
Temperature control accuracy	Within ±2°C (*) (difference between set temperature and actual sample temperature)
Temperature stability	Within ±0.5°C (*)
Applicable cell	10 mm cell (cell not supplied)

*:Room temperature : 25°C, sample : distilled water

Electronic thermostatted cell holder (P/N 131-0301/0302)

In protein and nucleic acid melting measurement, sample temperature can be changed continuously to determine variation in absorbance. Being of an electronic thermostatted type, this cell holder is capable of quick heating and cooling. Sample temperature can be increased and decreased isothermally. Because this holder is equipped with a stirrer, the internal cell temperature can be kept uniform. (Temperature control : R and S)



Specifications

<u> </u>	
Applicable cell	10 mm cell (not included in this unit)
Temperature range	0°C to 100°C (settable in increments of 0.1°C)
Temperature control accuracy	Within ±2°C (*) (difference between set
	temperature and actual sample temperature)
Temperature stability	Within ±0.5°C (*)
Provided with an isothermal regulating function	

*: Room temperature : 25°C, sample : distilled water circulatory water temperature : 22°C

Setting temperature : 10°C to 60°C

A circulatory thermostatic oven needs to be prepared separately.

*: Circulatory thermostatic oven not included

Micro flow cell unit

(P/N 210-2113)

Suitable for continuous measurement of a micro-quantity of sample.

Specifications

Cell capacity	70 µL
Optical path length	10 mm (quartz flow cell used)
Connection tubing	Teflon tube of outside diameter 2 mm and inside diameter 1 mm

Flow cell unit

(P/N 210-2173)

The inside of this cell is structured to minimize stagnation of liquid and adhesion of air bubbles.

Specifications		
Cell capacity	600 µL	
Optical path length	5 mm (quartz flow cell used)	
Connection tubing	Teflon tube of outside diameter 4 mm and inside diameter 3 mm	
Reference beam side	5 mm rectangular cell (standard accessory)	

LC flow cell unit (P/N 210-2131)

A flow cell especially designed for liquid chromatography.

6-cell positioner with temperature control

(P/N 2J1-0103/0104)

Six 10 mm cells can be mounted on the sample beam side, and they can be changed over automatically at certain intervals. (Temperature control : S only)



Specifications		
	Repeatability in cell changeover	Within ±0.5% (at 100%T)
Applicable cell		10 mm cell (not included in this unit)
	Setting temperature	20 to 40°C

*: Not including circulatory thermostatic oven and cell

Tandem cell holder (P/N 210-2115)

A maximum of three 10 mm cells can be mounted on each of the sample and reference beam sides. Sample temperature can be maintained at a constant level by circulating temperature-regulated water through the cell holder section. (Temperature control : R and S)

Specifications		
Temperature range	15 to 40°C	
Temperature stability	±0.3°C	

*: Not including circulatory thermostatic oven and cell

4-position rectangular long-path cell holder (P/N 150-0940)

Four rectangular long-path absorption cells can be mounted on the sample beam side, and they can be changed over externally.

Specifications

Cell length	100 mm, 50 mm to 10 mm cells applicable

5-position turret cell holder (P/N 210-2110)

Five 10 mm rectangular cells can be mounted on the sample beam side, and a micro-cell mask (200-1537, 200-1538) can be inserted in each cell holder. (Cells and micro-cell mask are not included.) It is recommended to prepare a set of five cells.



Part No.		Part name
	124-0352	10 mm quartz cell set (five cells in set)
	124-0378	10 mm glass cell set (five cells in set)

Rectangular long-path cell holder (P/N 210-2107)

Rectangular cells having the following optical path lengths are applicable: 10, 20, 30, 40, 50 and 100 mm.



Cylindrical long path cell holder (P/N 210-2108)

This holder is for cylindrical cell (ϕ 30mm)



Glass filter holder (P/N 210-2109)

Used for transmittance/absorbance measurement of a solid sheet sample such as glass filter.



Specifications	
Sample thickness	0.5 to 5 mm
Sample size	Minimum : 12 x 25 mm Maximum : 55 x 100 mm

Film holder

(P/N 210-2112)

Convenient for measurement of film-shaped samples.



 Film frame
 Width 25 mm, height 30 to 55 mm

 Beam aperture
 Width 10 mm, height 20 mm

φ150 integrating sphere accessory (P/N 2J2-0175)

Designed for diffuse reflectance measurement of a solid sample surface and absorbance measurement of a turbid sample. With an aperture ratio as small as 2%, this unit is usable for high-accuracy colorimetric measurement.



Specifications	
Wavelength range	350 to 750 nm
100%T line flatness	±0.5%T
Aperture ratio	2%
Light trap	Mountable

φ60 integrating sphere accessory(P/N 2J2-0176)

Designed for absorbance measurement of a turbid sample and reflection measurement of a solid sample surface.



Specifications

opeonedicite		
Wavelength range	250 to 800 nm	
100%T line flatness	±1%T	
Aperture ratio	7.8%	
Specular reflection measurement attachment	Standard-equipped	

5° specular reflectance accessory (P/N 2J2-0177)

Using mirror reflection of a sample, relative reflectance is measured with respect to the standard reflection plate (aluminum-evaporated plane mirror). Applicable to film thickness measurement and spectral reflectance measurement.



Polarizer holder

(P/N 210-2130)

Sample beam is linearly polarized for measurement of polarization characteristics or a sample is placed between the polarizer and analyzer for measurement of optical rotary power.



 Specifications

 Wavelength range
 400 to 750 nm

 Sample area
 Minimum 12 mm x 25 mm Maximum 55 mm x 100 mm

 Sample thickness
 0.5 to 5 mm

Optional program

Part No.	Part name
2J2-0311	Option Package program
2J2-0312	Report Generater program
2J2-0316	Nucleic Acid Measurement program
2J2-0317	GLP/GMP program

Option Package Program

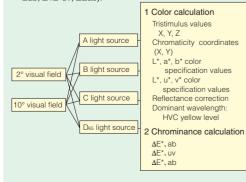
(P/N 2J2-0311)

Color Analysis

To define a color of light or any object, it is helpful to provide conventions concerning light sources, objects and eyes. Standard light for measurement is specified in JIS Z 8720, and color representation in XYZ color scheme is specified in JIS Z 8701.

The color analysis program is designed for diffuse reflectance measurement of a solid sample surface, making it possible to carry out high-accuracy color measurement analysis. Its measurement method conforms to JIS Z8722.

A photometric value ranging from 780 to 380 nm is taken in, and calculations are performed on tristimulus values (X, Y, Z), psychometric lightness values (L*, L), psychometric chroma coordinates (a*, b*, a, b), and chromaticity coordinates (x, y). With input of tristimulus values (X, Y, Z) of a standard sample and tristimulus values of an analyte sample, chrominance calculation is performed (Δ Eab, Δ 4E*uv, Δ Eab).



Application Measurement

Conforming to the test method for sheet glass transmittance and reflectance, specified in the JIS (Japanese Industrial Standards).

1.Visible Transmittance (Reflectance) Measurement Program

Spectral transmittance τv and spectral reflectance ρv of sheet glass are measured in the visible wavelength range. Using these measured values, visible light transmittance τv and visible light reflectance ρv based on relative luminous efficiency of CIE light adaptation are automatically calculated with respect to the standard light Des specified by CIE. (CIE:International Commission on Illumination)

	780 ΣDλ·Vλ·τ (λ) 380
τv=	780 ΣDλ·Vλ 380
0	780 ΣDλ·Vλ·ρ(λ) 380
ρv=	780 ΣDλ·Vλ 380

Dλ: Spectral distribu-tion of standard light D65

Vλ : Relative luminous efficiency of CIE light adaptation

2. Sum-of-Products Calculation Program

The abovementioned visible light transmittance (reflectance) and solar radiation transmittance (reflectance) conform to JIS R3106. This program is formulated as a general form for calculation of these values. For each wavelength, a measured value is multiplied by coefficient 1/K, and a total sum value is determined for normalization. A weight factor $\alpha(\lambda)$, wavelength range, and normalization factor can be set up arbitrarily in use of this program.

$$S = \frac{\sum_{\lambda_{1}}^{\lambda_{2}} (\lambda) \cdot \tau(\lambda)}{\sum_{\lambda_{1}}^{\lambda_{2}} \sum_{\lambda_{1}} (\lambda)} = \frac{1}{K} \sum_{\lambda_{1}}^{\lambda_{2}} \sum_{\lambda_{1}}^{\lambda_{2}} (\lambda) \cdot \tau(\lambda)$$
$$K = \sum_{\lambda_{1}}^{\lambda_{2}} (\lambda)$$

3.Weight Factor Input Program

With this program, a correction value (weight factor) for each wavelength interval $\Delta\lambda$ can be input in a wavelength range of λ 1 to λ 2. Using the input values, the sum-of-products program is carried out. Up to five wavelength intervals can be assigned individually, and up to 400 data points can be specified.

4.Spectrum Correction Program

A photometric value at each wavelength is multiplied by correction coefficient, and the result of multiplication is displayed and recorded in graph. A correction count value can be specified arbitrarily by the user. This program is particularly useful for absolute reflectance spectral measurement.

- $R(\lambda) = r(\lambda) \cdot Ro(\lambda)$
- $R(\lambda)$: Corrected data
- $r(\lambda)$: Measured data (%)
- $Ro(\lambda)$: Correction coefficient data

5.Correction Coefficient Input

This program is designed for input of correction coefficient data.Up to 400 points can be specified.

6.Film Thickness Calculation

In use with the reflectance accessory, this program allows the following measurements:

- A thickness of a film object is calculated according to the measured interference spectrum. The results of calculation are displayed on the CRT monitor and output onto the printer for recording.
- Photometric values of measured interference spectral peaks and valleys can be printed out automatically.
- A difference between standard film thickness and measured film thickness is calculated, and the resultant data can be displayed on the CRT monitor and output onto the printer for recording.

$$d = \frac{N-1}{2\sqrt{n^2 - \sin^2\theta}} \times \frac{1}{\frac{1}{\lambda_1} - \frac{1}{\lambda_2}} \times 10^{-1}$$

- d: Film thickness (µm)
- ... Value to be calculated
- N: Number of interference peaks
- ... Counted automatically n: Reflection factor
- ... Manually entered value *θ*: Angle of incidence
- ... Manually entered value
- λ_1 : First peak wavelength in spectrum (nm)
- λ_2 : Last peak wavelength in spectrum (nm)

U-3900/3900H

Model	U-3900	U-3900H	
Monochromator	Diffraction grating Single monochromator Seya-Namioka mount	Diffraction grating-diffraction grating Double monochromator Seya-Namioka mount	Spectrophotometer
Wavelength range	190 to 900 nm ^(*1)		control
Spectral bandpass	0.1, 0.5, 1, 2, 4, 5 nm (6 steps)		
Stray light	0.015%	0.00025%	
		NaNO2: 340 nm)	
Wavelength accuracy		after wavelength calibration)	
Wavelength setting repeatability		.05 nm	Measuring
Photometric mode		6R, E(S), E(R)	conditions
Photometric range	Abs : -3.8 to 3.8 Abs (effective range) %T : 0 to 300%T	Abs : -5.5 to 5.5 Abs(*2) (effective range) %T : 0 to 300%T	
Photometric accuracy (checked with NIST SRM930)	±0.002 Abs (0 to 0.5 Abs) ±0.003 Abs (0.5 to 1.0 Abs) ±0.006 Abs (0.5 to 1.0 Abs) ±0.3%T ±0.3%T ±0.0015 Abs (0 to 0.5 Abs) ±0.0015 Abs (0.5 to 1.0 Abs) ±0.003 Abs (1.0 to 2.0 Abs) ±0.01%T		Execution of
Photometric repeatability (checked with NIST SRM930)			measurement
Response	High resolu	ition, Standard	
Baseline flatness	Within ±0.0003 Abs (190 to 850 nm)	Within ±0.0004 Abs (190 to 850 nm)	
Baseline stability	Within 0.0002 Abs/hr (at 5	00 nm, 2 hours after power-on)	
Baseline memory	3 channels (system : 1	channel, user : 2 channels)	Recording/ Display
Wavelength scan speed	1.5, 3, 15, 30, 60, 120, 300, 600, 1200, 1800, 2400 nm/min		Display
Light source	Adjustment-free deuterium lamp D2 lamp): Ultraviolet region Adjustment-free tungsten iodine lamp (50 W)(WI lamp) : Visible region		
Light source changeover	Automatic changeover linked with wavelength Changeover wavelength : Selectable in a range of 325 to 370 nm)		
Sample compartment	Beam spacing: 100 mm 120 (W) × 300 (D) × 140 (H) mm		
Detector	Photo	multiplier	
Data processing unit	PC: OS	Windows [®] 7	
Dimensions (spectrophotometer main unit)	680 (W) × 692	(D) × 257 (H) mm	Data processing
Operating temperature/humidity	Temperature : 15 to 35°C, Humidity: 25 to 85% (non-condensing)		
Weight	45 kg (spectrophotometer main unit)		
Power consumption	100 V AC 50/60 Hz, 300 VA (excluding PC and printer)		

Software Functions (common to U-3900/U-3900H)

	Vavelength/Time Scan, urement and Data Proce	Photometry	
inious	arement and Data 11000	ssing	
ntrol 0100	elength shift (Go to λ) %T adjustment (auto zero) matic wavelength calibration cotor zero adjustment		
Con Con Auto	Measuring condition setting Condition loading Condition saving (desired number of files, file overwriting/deletion possible) Automatic start function (measuring conditions automatically set upon startup of software)		
easuring anditions	—	Condition setting for working curv (1st to 3rd order, segmented line) Standard data setting (20 standards, average of 20 data K factor input	
Reperies Rep	surement of spectrum/change w titive spectrum measurement ng of sampling interval surement with scan speed c traviolet region	Interrupt measurement	
	eline measurement (3 chann em baseline : 1 channel, us		
	Sample name Comment input Ruled line printout ON/OFF Measuring condition printout ON/OFF		
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iscellaneous	File conversion (ASCII/JCAMP) Setting of number of decimal places for display Cell length conversion Data transfer/graph copy to Microsoft [®] Excel Print preview Display of lamp ON time		
Standard	Equipment	Q'ty	

 Standard Equipment
 Q'ty

 Spectrophotometer main unit
 1 set

 Tools
 1 set

 Instruction manual
 1 set

NOTES: 1. Absorption cells are not included in the standard equipment, and thus should be prepared separately. 2. A PC set is not supplied as standard equipment. It should be prepared separately.

CAUTION: For correct operation, follow the instruction manual when using the instrument.

Specifications in this catalog are subject to change with or without notice, as Hitachi High-Tech Science Corporation continues to develop the latest technologies and products for our customers.

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NOTICE: The system is For Research Use Only, and is not intended for any animal or human therapeutic or diagnostic use.

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Tokyo, Japan

*1: Baseline flatness in a range of 190 to 850 nm Within ±0.0003 Abs (U-3900)

Within ±0.0004 Abs (U-3900H) *2: With 1%T attenuator

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